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(71) Applicant: **COHU GMBH** [DE/DE]; Geigelsteinstraße 6, 83059 Kolbermoor (DE).

(72) Inventors: **ENGELBRECHT, Stefan**; Georg-Dorrer-Straße 2, 83052 Bruckmühl (DE). **MEDERER, Christoph**; Matthias-Neff-Straße 11, 83075 Bad Feilnbach (DE). **WESTENHUBER, Mathias**; Sonnenfeld 10a, 83122 Samerberg (DE). **WAGNER, Markus**; Filzenstraße 18A, 83059 Kolbermoor (DE).

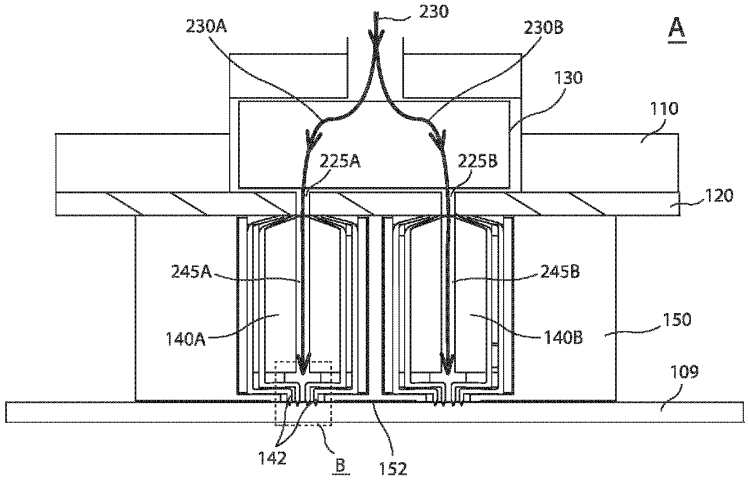
(74) Agent: **GALL, Ignaz**; Dilg, Haeusler, Schindelmann Patentanwaltsgesellschaft mbH, Leonrodstr. 58, 80636 München (DE).

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(54) Title: PROBE HEAD AND PROBE CARD FOR TESTING HIGH VOLTAGE SEMICONDUCTOR COMPONENTS AND SYSTEMS INCLUDING AND METHODS OF USING THE SAME

FIG. 2A



(57) Abstract: A probe head may include a plurality of test sites, each configured to test a different one of the electronic components. A probe head may include a plurality of groups of contact elements, each associated with a different test site and configured to contact a respective electronic component to be tested in the different test site. A probe head may include a plurality of gas supply channels, each passing through a respective test site and configured to supply pressurized gas to a respective group of contact elements associated with the respective test site.

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